

Fast identification of true critical paths in sequential circuits

Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan; Jürimägi, Lembit Microelectronics reliability 2018 / p. 252-261 : ill <https://doi.org/10.1016/j.microrel.2017.11.027> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Hierarchical timing-critical paths analysis in sequential circuits

Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan; Devadze, Sergei; Kostin, Sergei 2018 IEEE 28th International Symposium on Power and Timing Modeling, Optimization and Simulation (PATMOS 2018) : 2 – 4 July 2018, Spain 2018 / 6 p. : ill <https://doi.org/10.1109/PATMOS.2018.8464176>

A scalable technique to identify true critical paths in sequential circuits

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